

<b>Notice of References Cited</b>	Application/Control No. 10/751,176	Applicant(s)/Patent Under Reexamination GEIER ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,459,473 A	10-1995	Dempster et al.	342/357.12
*	B	US-6,009,118 A	12-1999	Tiemann et al.	375/150
*	C	US-6,532,251 B1	03-2003	King et al.	375/142
*	D	US-6,546,040 B1	04-2003	Eschenbach, Ralph F.	375/140
*	E	US-2003/0081660 A1	05-2003	King et al.	375/150
*	F	US-2003/0179813 A1	09-2003	Morita et al.	375/148
*	G	US-6,646,980 B1	11-2003	Yamamoto et al.	370/208
*	H	US-2003/0227963 A1	12-2003	Dafesh, Philip A.	375/149
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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